

Search Notes

Application/Control No.

10/676,976

Examiner

Stephen W. Smoot

Applicant(s)/Patent under
Reexamination

GLEW ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	31	12/17/2004	SWS
438	481	12/17/2004	SWS
438	494	12/17/2004	SWS
438	507	12/17/2004	SWS
438	695	12/17/2004	SWS
117	58	12/17/2004	SWS
117	95	12/17/2004	SWS
117	104	12/17/2004	SWS

*S.W.S.***INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words: SAGE - Selective Area Growth and Etch;	12/17/2004	<i>S.W.S.</i> SWS
Mask - Wafer, Substrate; Epitaxy; CVD.	12/17/2004	<i>S.W.S.</i> SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	12/17/2004	<i>S.W.S.</i> SWS
PLUS Search	12/15/2004	<i>S.W.S.</i> SWS